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#1   ((cluster master failover)<in>metadata)

#2   ((cluster<in>metadata) <and> (master<in>metadata))<and> (failover<in>metadata)

#3   ((cluster<in>metadata) <and> (master<in>metadata))<and> (failover<in>metadata)

#4   ((master <in>metadata) <and> (fault management<in>metadata))

#5   (fault management<in>metadata)

#6   ((fault managment <in>metadata) <and> (master<in>metadata))

#7   ((fault management <in>metadata) <and> (secondary device<in>metadata))

#8   ((fault management <in>metadata) <and> (lead<in>metadata))<or> (leader<in>metadata)

#9   ((fault management<in>metadata) <and> (master<in>metadata))<and> (device<in>metadata)

#10 ((fault managment <in>metadata) <and> (controlling <in>metadata))<and> (device<in>metadata)

#11 ((fault management<in>metadata) <and> (fail over <in>metadata))<or> (fault or failover<in>metadata)

#12 ((fault management <in>metadata) <and> (network <in>metadata))<and> (failover or fail over<in>metadata)

#13 ((fault management <in>metadata) <and> (network <in>metadata))<and> (failover or fail over<in>metadata)

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CNF = IEE Conference,　IEEE STD = IEEE Standard

1.　**Ethernet OAM: key enabler for carrier class metro ethernet services**
　　McFarland, M.; Salam, S.; Checker, R.;
　　Communications Magazine, IEEE
　　Volume 43,　Issue 11,　Nov. 2005 Page(s):152 - 157

　　IEEE JNL